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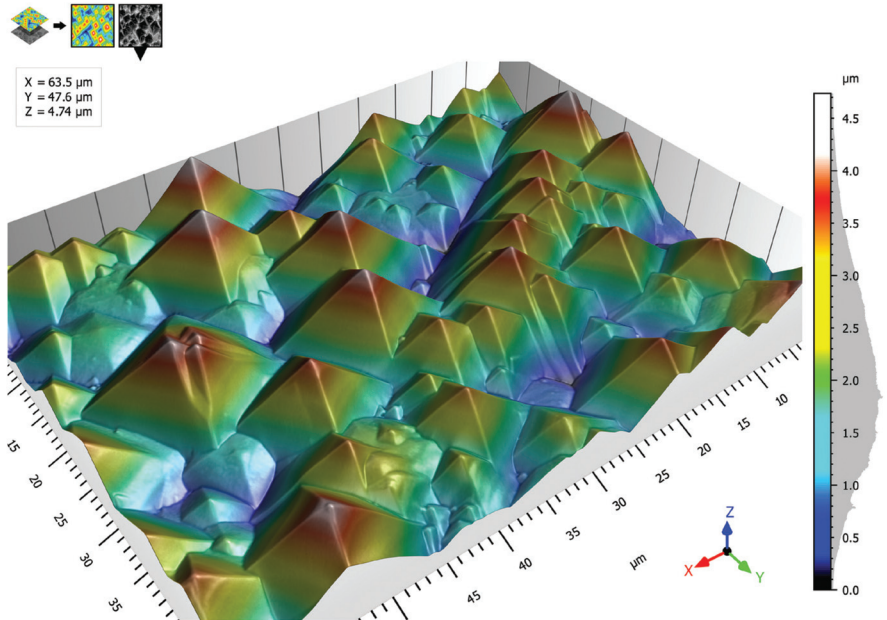
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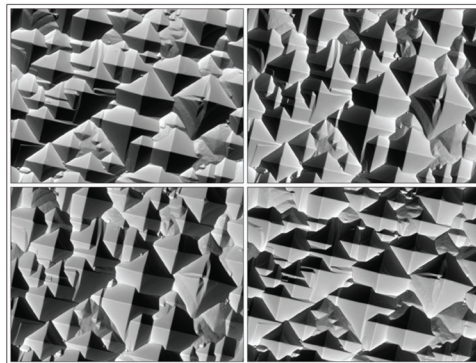


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Height Parameters		
Sq	1.38 µm	Root-mean-square height
Ssk	0.148	Skewness
Sku	2.63	Kurtosis
Sp	4.32 µm	Maximum peak height
Sv	4.07 µm	Maximum pit height
Sz	8.39 µm	Maximum height
Sa	1.12 µm	Arithmetic mean height
Functional Parameters		
Smr	0.642 %	Areal material ratio
Smc	1.88 µm	Inverse areal material ratio
Sxp	2.45 µm	Extreme peak height
ISO 12781		
Flatness Parameters		
FLTt	5.40 µm	Peak-to-valley flatness deviation of the surface
FLTp	2.58 µm	Peak-to-reference flatness deviation

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